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/ Ruth Montalvo Date: 04/29/05

Customer No.

026418

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Attorney's Docket No.:

GK-ZEI-3269/500343.20289

U.S. Application No.:

International Application No.:

PCT/EP2004/006302

International Filing Date:

JUNE 11, 2004

11 JUNE 2004

Priority Date Claimed:

JUNE 12, 2003

12 JUNE 2003

Title of Invention:

METHOD FOR DETERMINING THE IMAGE QUALITY OF AN OPTICAL

IMAGING SYSTEM

Applicant(s) for (DO/EO/US):

Thomas ENGEL and Herbert GROSS

Mail Stop PCT Commissioner For Patents P.O. Box 1450 Alexandria, VA 22313-450

AX

INFORMATION DISCLOSURE STATEMENT

SIR:

Applicant herewith submits together with the simultaneously filed National Phase application of PCT/EP2004/006302, a copy of the International Search Report (PCT/ISA/210) dated October 20, 2004 and German Examination Report (103 27 019.1) dated March 4, 2004, citing some of the following references:

	Document Number	Date	Name and/or Country	English Translation		
AA	5,066,119	11/19/1991	Bertand			
AB	2002/0057495	05/16/2002	Kuramoto			
AL	38 42 144	06/21/1990	Germany	Abstract only		
AM	95/34800	12/21/1995	WIPO			
AN	10-170399	06/26/1998	Japan	Abstract only		
AO	99/66308	12/23/1999	WIPO			
AP	1 079 223	02/28/2001	European			
AQ	1 246 014	10/02/2002	European			
AR	101 54 125	05/22/2003	Germany	Abstract only		
	OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)					

Literature: Joseph Geary, "Wavefront sensors", SPIE Press 1995

AY Literature: Daniel Malacara, "Optical Shop Testing", Wiley Verlag 1992 Accompanying this Information Disclosure Statement and form PTO-1449 are copies of the 7 foreign documents including 3 English Abstracts, first pages of the 2 U.S. documents except articles AX and AY. Articles AX-AY are mentioned on page 3 of the substitute specification.

The USPTO waived the requirement under 37 C.F.R. §1.98(a)(2)(i) for submitting copies of US patents and US patent application publications in all U.S. applications filed after June 30, 2003.

This submission is not an admission that the information disclosed in the documents is material to the patentability of the invention disclosed and/or claimed in the above-identified application.

Respectfully submitted,

GHK:ram 04/29/05

Tel. (212) 521-5400

Enclosures:

Search Reports (PCT/ISA/210); German Examination Report PTO-1449; 2 U.S. first pages 7 documents

3 English Abstracts

Gerald H. Kiel - Reg. No. 25,116

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LIST OF PRIOR ART CITED BY APPLICANT

JC20 Rec'd PCT/PTO 2 9 APR 2005 (Filed on April 29, 2005)

Docket No.

GK-ZEI-3269/500343.20289

Applicant(s):

Thomas ENGEL and Herbert GROSS

Application No.

(Int'l Appln No. PCT/EP2004/006302 11JUNE04) Group:

Filed:

Concurrently herewith - April 29, 2005

Examiner:

é,

U.S. PATENT DOCUMENTS

Exam. Init		Document Number	Date	Name	Class	Sub- Class	Filing Date Appropriate
	AA	5,066,119	11/19/1991	Bertand			
_	AB	2002/0057495	05/16/2002	Kuramoto			
	AC						
	AD			- 1			
	AE						
	AF						
	AG						
	AH	:					
	Al		1				
	AJ						
·	AK						

FOREIGN PATENT DOCUMENTS

			TOTAL CONTRACTOR					
		Document Number	Date	Country	CLASS	Sub- Class	Translation YES NO	
	AL	38 42 144	06/21/1990	Germany			Abstract only	
	AM	95/34800	12/21/1995	WIPO				
	AN	10-170399	06/26/1998	Japan			Abstract only	
	AO	99/66308	12/23/1999	WIPO				
	AP	1 079 223	02/28/2001	European				
-	AQ	1 246 014	10/02/2002	European				
	AR	101 54 125	05/22/2003	Germany			Abstract only	
	AS	1						
	AT							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AX	Literature: Joseph Geary, "Wavefront sensors", SPIE Press 1995
AY	Literature: Daniel Malacara, "Optical Shop Testing", Wiley Verlag 1992
AZ	

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Examiner:		Date:	

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.